

<b>Notice of References Cited</b>	Application/Control No. 10/811,741		Applicant(s)/Patent Under Reexamination LAM ET AL.	
	Examiner Paul D. Kim		Art Unit 3729	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,738,566	04-1998	Li et al.	451/28
*	B	US-5,023,991	06-1991	Smith, Alan B.	29/603.09
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"The effect of lapping method on the thermal reliability of a GMR head based on Black's equation"; Yufeng Li; Meyer, D.; Magnetics, IEEE Transactions on Volume 37, Issue 2, Part 1, March 2001; Pages:974 - 979.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.